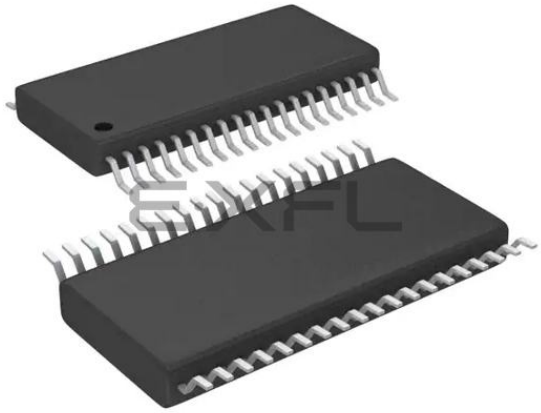
Infineon Technologies - XMC1100T038F0016AAXUMA1 Datasheet



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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Obsolete
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	32MHz
Connectivity	I²C, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, I²S, POR, PWM, WDT
Number of I/O	26
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 5.5V
Data Converters	A/D 12x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	38-TFSOP (0.173", 4.40mm Width)
Supplier Device Package	PG-TSSOP-38-9
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xmc1100t038f0016aaxuma1

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XMC1100 Data Sheet

Revision History: V1.4 2014-05

Previous Version: V1.3	
Page	Subjects
Page 10	ADC channels of Table 2 is updated. Table 3 is added.
Page 10	Description for Chip Identification Number of Section 1.4 is updated.
Page 17	The pad type is corrected for P1.6 in Table 6.
Page 29	The t_{C12} , f_{C12}, t_{C10}, f_{C10}, t_{C8} and f_{C8} parameters are updated in Table 12.
Page 32	Figure 8 is added.
Page 33	The t_{SR} and t_{TSAL} parameters are updated in Table 13.
Page 36	Parameter name for t_{PSER} is updated. The $N_{WSFLASH}$ parameter and test condition for t_{RET} are added to Table 16.
Page 39	The min value for V_{DDPBO} parameter is added to Table 18. Footnote 1 is updated.
Page 41	The Δf_{LTT} parameter is added to Table 19.
Page 47	Figure 13 is added.

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About this Document

This Data Sheet is addressed to embedded hardware and software developers. It provides the reader with detailed descriptions about the ordering designations, available features, electrical and physical characteristics of the XMC1100 series devices.

The document describes the characteristics of a superset of the XMC1100 series devices. For simplicity, the various device types are referred to by the collective term XMC1100 throughout this document.

XMC1000 Family User Documentation

The set of user documentation includes:

- **Reference Manual**
  – decribes the functionality of the superset of devices.
- **Data Sheets**
  – list the complete ordering designations, available features and electrical characteristics of derivative devices.
- **Errata Sheets**
  – list deviations from the specifications given in the related Reference Manual or Data Sheets. Errata Sheets are provided for the superset of devices.

Attention: Please consult all parts of the documentation set to attain consolidated knowledge about your device.

Application related guidance is provided by **Users Guides** and **Application Notes**.

Please refer to **http://www.infineon.com/xmc1000** to get access to the latest versions of those documents.

1 Summary of Features

The XMC1100 devices are members of the XMC1000 family of microcontrollers based on the ARM Cortex-M0 processor core. The XMC1100 series devices are designed for general purpose applications.

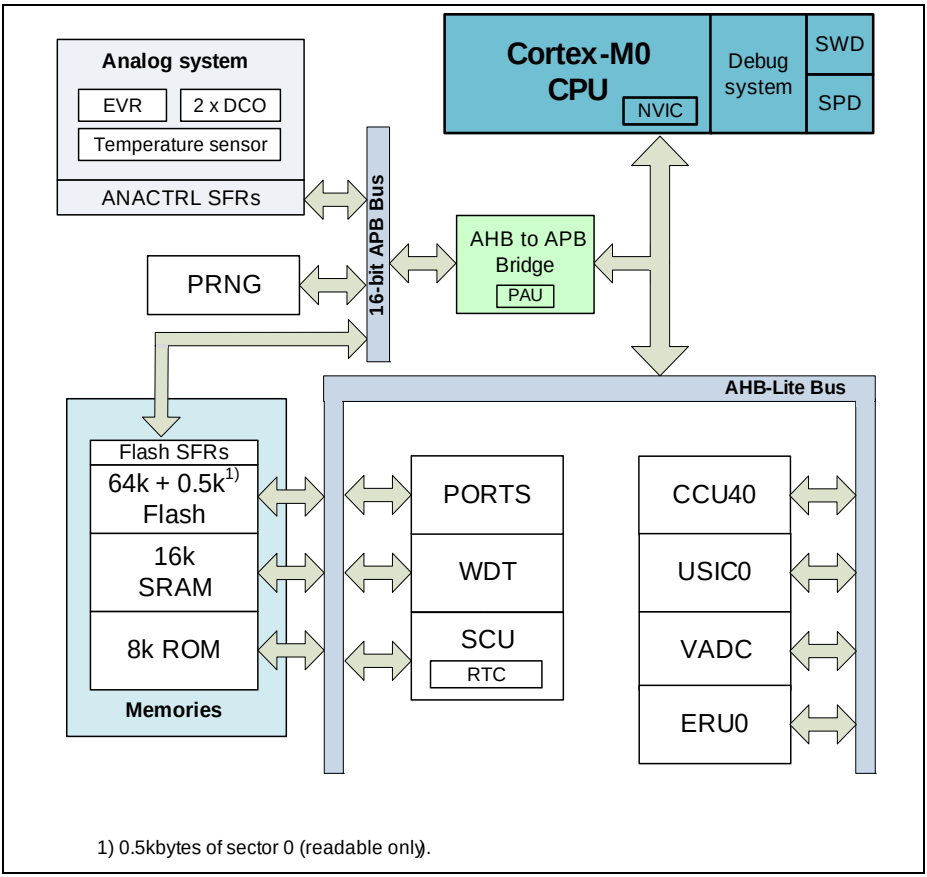

Figure 1 System Block Diagram

CPU Subsystem

- CPU Core
  - High Performance 32-bit ARM Cortex-M0 CPU
  - Most of 16-bit Thumb instruction set
  - Subset of 32-bit Thumb2 instruction set

  - High code density with 32-bit performance
  - Single cycle 32-bit hardware multiplier
  - System timer (SysTick) for Operating System support
  - Ultra low power consumption
- Nested Vectored Interrupt Controller (NVIC)
- Event Request Unit (ERU) for programmable processing of external and internal service requests

On-Chip Memories

- 8 kbytes on-chip ROM
- 16 kbytes on-chip high-speed SRAM
- up to 64 kbytes on-chip Flash program and data memory

On-Chip Peripherals

- Two Universal Serial Interface Channels (USIC), usable as UART, double-SPI, quad-SPI, IIC, IIS and LIN interfaces
- A/D Converters, up to 12 channels, includes a 12-bit analog to digital converter
- Capture/Compare Units 4 (CCU4) for use as general purpose timers
- Window Watchdog Timer (WDT) for safety sensitive applications
- Real Time Clock module with alarm support (RTC)
- System Control Unit (SCU) for system configuration and control
- Pseudo random number generator (PRNG), provides random data with fast generation times
- Temperature Sensor (TSE)

Input/Output Lines

- Programmable port driver control module (PORTS)
- Individual bit addressability
- Tri-stated in input mode
- Push/pull or open drain output mode
- Configurable pad hysteresis

On-Chip Debug Support

- Support for debug features: 4 breakpoints, 2 watchpoints
- Various interfaces: ARM serial wire debug (SWD), single pin debug (SPD)

1.1 Ordering Information

The ordering code for an Infineon microcontroller provides an exact reference to a specific product. The code “XMC1<DDD>-<Z><PPP><T><FFFF>” identifies:

- <DDD> the derivatives function set

Table 1 Synopsis of XMC1100 Device Types (cont'd)

Derivative	Package	Flash Kbytes	SRAM Kbytes
XMC1100-Q040F0032	PG-VQFN-40-13	32	16
XMC1100-Q040F0064	PG-VQFN-40-13	64	16

1.3 Device Type Features

The following table lists the available features per device type.

Table 2 Features of XMC1100 Device Types[1)]

Derivative	ADC channel
XMC1100-T016	6
XMC1100-T038	12
XMC1100-Q024	8
XMC1100-Q040	12

1) Features that are not included in this table are available in all the derivatives

Table 3 ADC Channels

Package	VADC0 G0	VADC0 G1
PG-TSSOP-16	CH0..CH5	–
PG-TSSOP-38	CH0..CH7	CH1, CH5 .. CH7
PG-VQFN-24	CH0..CH7	–
PG-VQFN-40	CH0..CH7	CH1, CH5 .. CH7

1.4 Chip Identification Number

The Chip Identification Number allows software to identify the marking. It is a 8 words value with the most significant 7 words stored in Flash configuration sector 0 (CS0) at address location : 1000 $0F00_H$ (MSB) - 1000 $0F1B_H$ (LSB). The least significant word and most significant word of the Chip Identification Number are the value of registers DBGROMID and IDCHIP, respectively.

Table 4 XMC1100 **Chip Identification Number**

Derivative	Value	Marking
XMC1100-T016F0008	00011032 01CF00FF 00001F37 00000000 00000B00 00001000 00003000 $101ED083_H$	AA
XMC1100-T016F0016	00011032 01CF00FF 00001F37 00000000 00000B00 00001000 00005000 $101ED083_H$	AA
XMC1100-T016F0032	00011032 01CF00FF 00001F37 00000000 00000B00 00001000 00009000 $101ED083_H$	AA
XMC1100-T016F0064	00011032 01CF00FF 00001F37 00000000 00000B00 00001000 00011000 $101ED083_H$	AA
XMC1100-T016X0064	00011033 01CF00FF 00001F37 00000000 00000B00 00001000 00011000 $101ED083_H$	AA
XMC1100-T038F0016	00011012 01CF00FF 00001F37 00000000 00000B00 00001000 00005000 $101ED083_H$	AA
XMC1100-T038F0032	00011012 01CF00FF 00001F37 00000000 00000B00 00001000 00009000 $101ED083_H$	AA
XMC1100-T038F0064	00011012 01CF00FF 00001F37 00000000 00000B00 00001000 00011000 $101ED083_H$	AA
XMC1100-T038X0064	00011013 01CF00FF 00001F37 00000000 00000B00 00001000 00011000 $101ED083_H$	AA
XMC1100-Q024F0008	00011062 01CF00FF 00001F37 00000000 00000B00 00001000 00003000 $101ED083_H$	AA
XMC1100-Q024F0016	00011062 01CF00FF 00001F37 00000000 00000B00 00001000 00005000 $101ED083_H$	AA
XMC1100-Q024F0032	00011062 01CF00FF 00001F37 00000000 00000B00 00001000 00009000 $101ED083_H$	AA
XMC1100-Q024F0064	00011062 01CF00FF 00001F37 00000000 00000B00 00001000 00011000 $101ED083_H$	AA
XMC1100-Q040F0016	00011042 01CF00FF 00001F37 00000000 00000B00 00001000 00005000 $101ED083_H$	AA
XMC1100-Q040F0032	00011042 01CF00FF 00001F37 00000000 00000B00 00001000 00009000 $101ED083_H$	AA
XMC1100-Q040F0064	00011042 01CF00FF 00001F37 00000000 00000B00 00001000 00011000 $101ED083_H$	AA

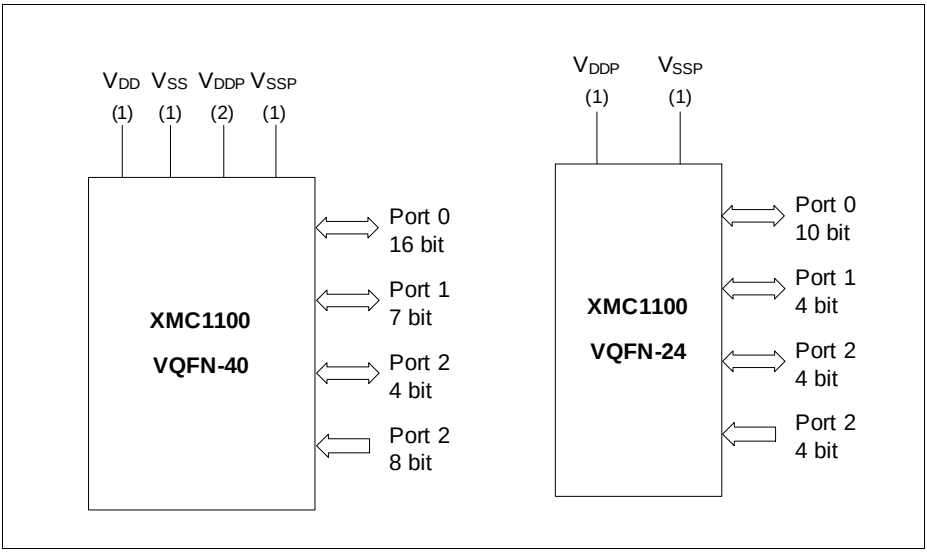

Figure 3 XMC1100 Logic Symbol for VQFN-24 and VQFN-40

2.2 Pin Configuration and Definition

The following figures summarize all pins, showing their locations on the different packages.

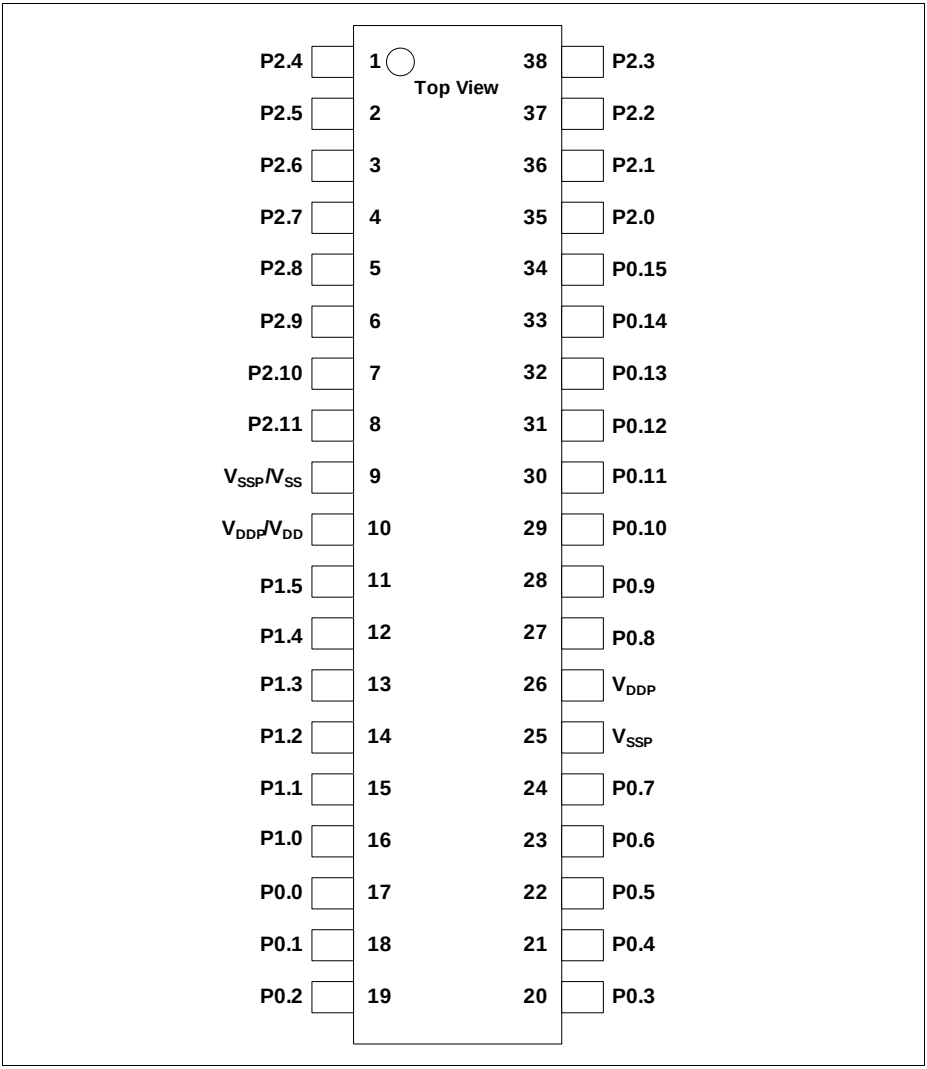

Figure 4 XMC1100 **PG-TSSOP-38 Pin Configuration** (top view)

3 Electrical Parameter

This section provides the electrical parameter which are implementation-specific for the XMC1100.

3.1 General Parameters

3.1.1 Parameter Interpretation

The parameters listed in this section represent partly the characteristics of the XMC1100 and partly its requirements on the system. To aid interpreting the parameters easily when evaluating them for a design, they are indicated by the abbreviations in the “Symbol” column:

- **CC**
  Such parameters indicate **C**ontroller **C**haracteristics, which are distinctive feature of the XMC1100 and must be regarded for a system design.
- **SR**
  Such parameters indicate **S**ystem **R**equirements, which must be provided by the application system in which the XMC1100 is designed in.

3.2 DC Parameters

3.2.1 Input/Output Characteristics

Table 11 provides the characteristics of the input/output pins of the XMC1100.

Table 11 Input/Output Characteristics (Operating Conditions apply)

Parameter	Symbol		Limit Values		Unit	Test Conditions
			Min.	Max.		
Output low voltage on port pins (with standard pads)	V_{OLP}	CC	–	1.0	V	I_{OL} = 11 mA (5 V) I_{OL} = 7 mA (3.3 V)
			–	0.4	V	I_{OL} = 5 mA (5 V) I_{OL} = 3.5 mA (3.3 V)
Output low voltage on high current pads	V_{OLP1}	CC	–	1.0	V	I_{OL} = 50 mA (5 V) I_{OL} = 25 mA (3.3 V)
			–	0.32	V	I_{OL} = 10 mA (5 V)
			–	0.4	V	I_{OL} = 5 mA (3.3 V)
Output high voltage on port pins (with standard pads)	V_{OHP}	CC	V_{DDP} - 1.0	–	V	I_{OH} = -10 mA (5 V) I_{OH} = -7 mA (3.3 V)
			V_{DDP} - 0.4	–	V	I_{OH} = -4.5 mA (5 V) I_{OH} = -2.5 mA (3.3 V)
Output high voltage on high current pads	V_{OHP1}	CC	V_{DDP} - 0.32	–	V	I_{OH} = -6 mA (5 V)
			V_{DDP} - 1.0	–	V	I_{OH} = -8 mA (3.3 V)
			V_{DDP} - 0.4	–	V	I_{OH} = -4 mA (3.3 V)
Input low voltage on port pins (Standard Hysteresis)	V_{ILPS}	SR	–	0.19 × V_{DDP}	V	CMOS Mode (5 V, 3.3 V & 2.2 V)
Input high voltage on port pins (Standard Hysteresis)	V_{IHPS}	SR	0.7 × V_{DDP}	–	V	CMOS Mode (5 V, 3.3 V & 2.2 V)
Input low voltage on port pins (Large Hysteresis)	V_{ILPL}	SR	–	0.08 × V_{DDP}	V	CMOS Mode (5 V, 3.3 V & 2.2 V)[3)]

Table 11 Input/Output Characteristics (Operating Conditions apply) (cont'd)

Parameter	Symbol		Limit Values		Unit	Test Conditions
			Min.	Max.		
Input high voltage on port pins (Large Hysteresis)	V_{IHPL}	SR	0.85 × V_{DDP}	–	V	CMOS Mode (5 V, 3.3 V & 2.2 V)[3]
Input Hysteresis[1]	HYS	CC	0.08 × V_{DDP}	–	V	CMOS Mode (5 V), Standard Hysteresis
			0.03 × V_{DDP}	–	V	CMOS Mode (3.3 V), Standard Hysteresis
			0.02 × V_{DDP}	–	V	CMOS Mode (2.2 V), Standard Hysteresis
			0.5 × V_{DDP}	0.75 × V_{DDP}	V	CMOS Mode(5 V), Large Hysteresis
			0.4 × V_{DDP}	0.75 × V_{DDP}	V	CMOS Mode(3.3 V), Large Hysteresis
			0.2 × V_{DDP}	0.65 × V_{DDP}	V	CMOS Mode(2.2 V), Large Hysteresis
Pull-up resistor on port pins	R_{PUP}	CC	20	50	kohm	$V_{IN} = V_{SSP}$
Pull-down resistor on port pins	R_{PDP}	CC	20	50	kohm	$V_{IN} = V_{DDP}$
Input leakage current[2]	I_{OZP}	CC	-1	1	µA	$0 < V_{IN} < V_{DDP}$, $T_A \leq 105$ °C
Overload current on any pin	I_{OVP}	SR	-5	5	mA	
Absolute sum of overload currents	$\Sigma\|I_{OV}\|$	SR	–	25	mA	[3]
Voltage on any pin during V_{DDP} power off	V_{PO}	SR	–	0.3	V	[4]
Maximum current per pin (excluding P1, V_{DDP} and V_{SS})	I_{MP}	SR	-10	11	mA	–
Maximum current per high currrent pins	I_{MP1A}	SR	-10	50	mA	–

Table 11 Input/Output Characteristics (Operating Conditions apply) (cont'd)

Parameter	Symbol		Limit Values		Unit	Test Conditions
			Min.	Max.		
Maximum current into V_{DDP} (TSSOP28/16, VQFN24)	I_{MVDD1}	SR	–	130	mA	3)
Maximum current into V_{DDP} (TSSOP38, VQFN40)	I_{MVDD2}	SR	–	260	mA	3)
Maximum current out of V_{SS} (TSSOP28/16, VQFN24)	I_{MVSS1}	SR	–	130	mA	3)
Maximum current out of V_{SS} (TSSOP38, VQFN40)	I_{MVSS2}	SR	–	260	mA	3)

1) Not subject to production test, verified by design/characterization. Hysteresis is implemented to avoid meta stable states and switching due to internal ground bounce. It cannot be guaranteed that it suppresses switching due to external system noise.

2) An additional error current (I_{INJ}) will flow if an overload current flows through an adjacent pin.

3) Not subject to production test, verified by design/characterization.

4) Not subject to production test, verified by design/characterization. However, for applications with strict low power-down current requirements, it is mandatory that no active voltage source is supplied at any GPIO pin when V_{DDP} is powered off.

3.2.4 Power Supply Current

The total power supply current defined below consists of a leakage and a switching component.

Application relevant values are typically lower than those given in the following tables, and depend on the customer's system operating conditions (e.g. thermal connection or used application configurations).

Table 14 Power Supply Parameters[1)]

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.[2)]	Max.		
Active mode current[3)]	I_{DDPA} CC	–	8.4	11.0	mA	f_{MCLK} = 32 MHz f_{PCLK} = 64 MHz
		–	3.7	–	mA	f_{MCLK} = 1 MHz f_{PCLK} = 1 MHz
Sleep mode current Peripherals clock enabled[4)]	I_{DDPSE} CC	–	5.9	–	mA	f_{MCLK} = 32 MHz f_{PCLK} = 64 MHz
Sleep mode current Peripherals clock disabled[5)]	I_{DDPSD} CC	–	1.2	–	mA	f_{MCLK} = 1 MHz f_{PCLK} = 1 MHz
Deep Sleep mode current[6)]	I_{DDPDS} CC	–	0.24	–	mA	
Wake-up time from Sleep to Active mode[7)]	t_{SSA} CC	–	6	–	cycles	
Wake-up time from Deep Sleep to Active mode[8)]	t_{DSA} CC	–	280	–	µsec	

1) Not all parameters are 100% tested, but are verified by design/characterisation and test correlation.
2) The typical values are measured at T_A = + 25 °C and V_{DDP} = 5 V.
3) CPU and all peripherals clock enabled, Flash is in active mode.
4) CPU is sleep, all peripherals clock enabled and Flash is in active mode.
5) CPU is sleep, Flash is powered down and code executed from RAM after wake-up.
6) CPU is sleep, peripherals clock disabled, Flash is powered down and code executed from RAM after wake-up.
7) CPU is sleep, Flash is in active mode during sleep mode.
8) CPU is sleep, Flash is in power down mode during deep sleep mode.

Table 15 provides the active current consumption of some modules operating at 5 V power supply at 25 °C. The typical values shown are used as a reference guide on the current consumption when these modules are enabled.

Table 15 Typical Active Current Consumption[1)]

Active Current Consumption	Symbol	Limit Values	Unit	Test Condition
		Typ.		
Baseload current	I_{CPUDDC}	5.04	mA	Modules including Core, SCU, PORT, memories, ANATOP[2)]
VADC and SHS	I_{ADCDDC}	3.4	mA	Set CGATCLR0.VADC to 1[3)]
USIC0	$I_{USIC0DDC}$	0.87	mA	Set CGATCLR0.USIC0 to 1[4)]
CCU40	$I_{CCU40DDC}$	0.94	mA	Set CGATCLR0.CCU40 to 1[5)]
WDT	I_{WDTDDC}	0.03	mA	Set CGATCLR0.WDT to 1[6)]
RTC	I_{RTCDDC}	0.01	mA	Set CGATCLR0.RTC to 1[7)]

1) Not subject to production test, verified by design/characterisation.

2) Baseload current is measured with device running in user mode, MCLK=PCLK=32 MHz, with an endless loop in the flash memory. The clock to the modules stated in CGATSTAT0 are gated.

3) Active current is measured with: module enabled, MCLK=32 MHz, running in auto-scan conversion mode

4) Active current is measured with: module enabled, alternating messages sent to PC at 57.6kbaud every 200ms

5) Active current is measured with: module enabled, MCLK=PCLK=32 MHz, 1 CCU4 slice for PWM switching from 1500Hz and 1000Hz at regular intervals, 1 CCU4 slice in capture mode for reading period and duty cycle

6) Active current is measured with: module enabled, MCLK=32 MHz, time-out mode; WLB = 0, WUB = 0x00008000; WDT serviced every 1s

7) Active current is measured with: module enabled, MCLK=32 MHz, Periodic interrupt enabled

3.3.3 Power-Up and Supply Threshold Charcteristics

Table 18 provides the characteristics of the supply threshold in XMC1100.

Table 18 Power-Up and Supply Threshold Parameters (Operating Conditions apply) [1]

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
V_{DDP} ramp-up time	t_{RAMPUP} SR	V_{DDP}/ $S_{VDDPrise}$	–	10^7	µs	
V_{DDP} slew rate	S_{VDDPOP} SR	0	–	0.1	V/µs	Slope during normal operation
	S_{VDDP10} SR	0	–	10	V/µs	Slope during fast transient within +/- 10% of V_{DDP}
	$S_{VDDPrise}$ SR	0	–	10	V/µs	Slope during power-on or restart after brownout event
	$S_{VDDPfall}$ [2] SR	0	–	0.25	V/µs	Slope during supply falling out of the +/-10% limits[3]
V_{DDP} prewarning voltage	V_{DDPPW} CC	2.1	2.25	2.4	V	ANAVDEL.VDEL_ SELECT = 00_B
		2.85	3	3.15	V	ANAVDEL.VDEL_ SELECT = 01_B
		4.2	4.4	4.6	V	ANAVDEL.VDEL_ SELECT = 10_B
V_{DDP} brownout reset voltage	V_{DDPBO} CC	1.55	1.62	1.75	V	calibrated, before user code starts running
Start-up time from power-on reset	t_{SSW} SR	–	320	–	µs	Time to the first user code instruction[4]

1) Not all parameters are 100% tested, but are verified by design/characterisation.

2) A capacitor of at least 100 nF has to be added between V_{DDP} and V_{SSP} to fulfill the requirement as stated for this parameter.

3.3.5 Serial Wire Debug Port (SW-DP) Timing

The following parameters are applicable for communication through the SW-DP interface.

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 21 SWD Interface Timing Parameters(Operating Conditions apply)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
SWDCLK high time	t_1 SR	50	–	500000	ns	–
SWDCLK low time	t_2 SR	50	–	500000	ns	–
SWDIO input setup to SWDCLK rising edge	t_3 SR	10	–	–	ns	–
SWDIO input hold after SWDCLK rising edge	t_4 SR	10	–	–	ns	–
SWDIO output valid time after SWDCLK rising edge	t_5 CC	–	–	68	ns	C_L = 50 pF
		–	–	62	ns	C_L = 30 pF
SWDIO output hold time from SWDCLK rising edge	t_6 CC	4	–	–	ns	

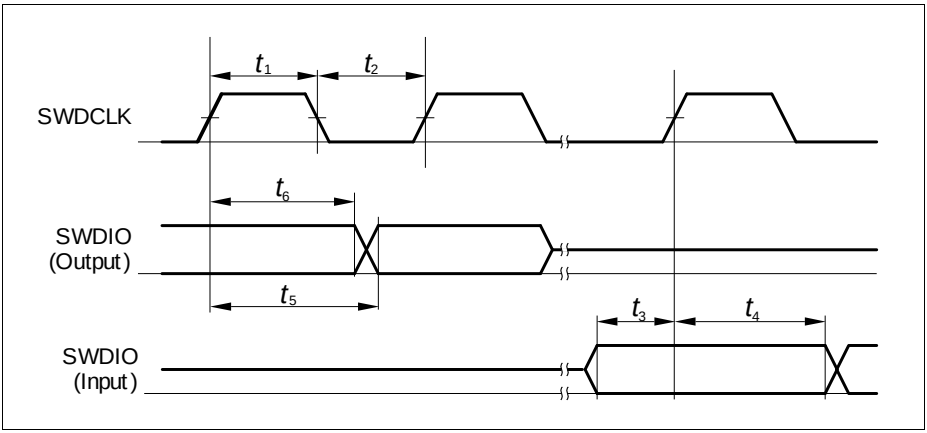

Figure 14 SWD Timing

3.3.7 Peripheral Timings

Note: These parameters are not subject to production test, but verified by design and/or characterization.

3.3.7.1 Synchronous Serial Interface (USIC SSC) Timing

The following parameters are applicable for a USIC channel operated in SSC mode.

Note: Operating Conditions apply.

Table 23 USIC SSC Master Mode Timing

Parameter	Symbol		Values			Unit	Note / Test Condition
			Min.	Typ.	Max.		
Slave select output SELO active to first SCLKOUT transmit edge	t_1	CC	80	–	–	ns	
Slave select output SELO inactive after last SCLKOUT receive edge	t_2	CC	0	–	–	ns	
Data output DOUT[3:0] valid time	t_3	CC	-10	–	10	ns	
Receive data input DX0/DX[5:3] setup time to SCLKOUT receive edge	t_4	SR	80	–	–	ns	
Data input DX0/DX[5:3] hold time from SCLKOUT receive edge	t_5	SR	0	–	–	ns	

Table 24 USIC SSC Slave Mode Timing

Parameter	Symbol		Values			Unit	Note / Test Condition
			Min.	Typ.	Max.		
Select input DX2 setup to first clock input DX1 transmit edge[1)]	t_{10}	SR	10	–	–	ns	
Select input DX2 hold after last clock input DX1 receive edge[1)]	t_{11}	SR	10	–	–	ns	

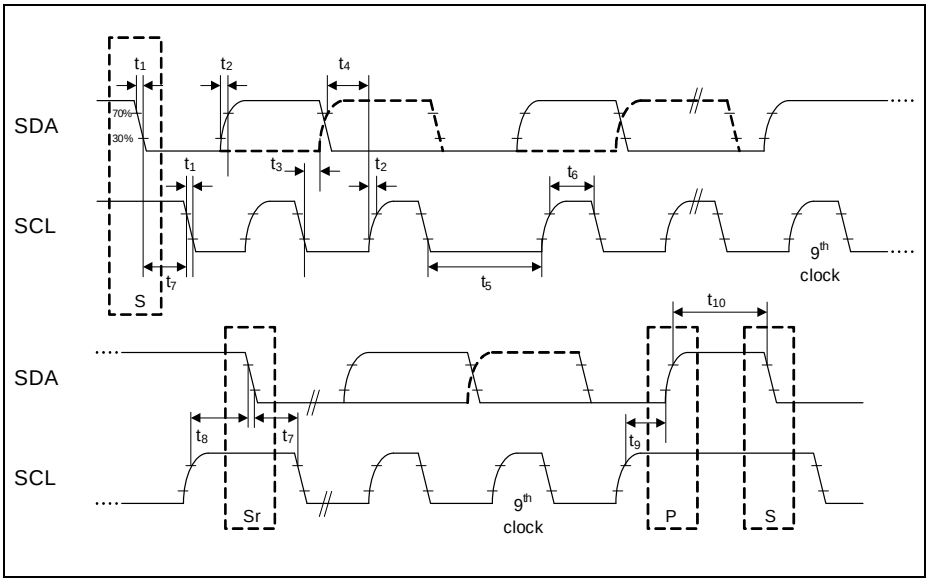

Figure 16 USIC IIC Stand and Fast Mode Timing

3.3.7.3 Inter-IC Sound (IIS) Interface Timing

The following parameters are applicable for a USIC channel operated in IIS mode.

Note: Operating Conditions apply.

Table 27 USIC IIS Master Transmitter Timing

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Clock period	t_1 CC	$2/f_{MCLK}$	-	-	ns	$V_{DDP} \geq 3$ V
		$4/f_{MCLK}$	-	-	ns	$V_{DDP} < 3$ V
Clock HIGH	t_2 CC	0.35 x t_{1min}	-	-	ns	
Clock Low	t_3 CC	0.35 x t_{1min}	-	-	ns	
Hold time	t_4 CC	0	-	-	ns	
Clock rise time	t_5 CC	-	-	0.15 x t_{1min}	ns	

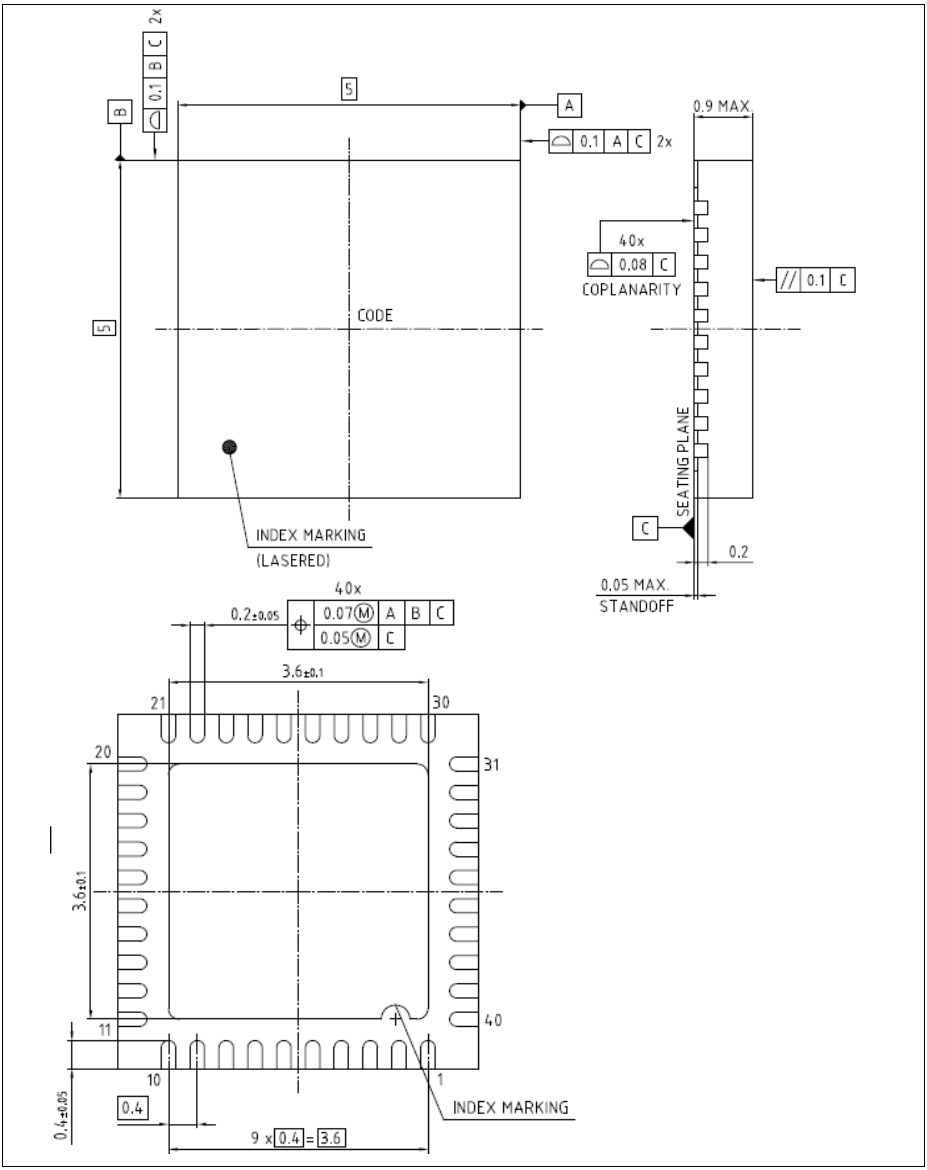

Figure 22 PG-VQFN-40-13

All dimensions in mm.